

# **Differential Imaging Microscopy of Physically Complex Surfaces Undergoing Atmospheric Corrosion**

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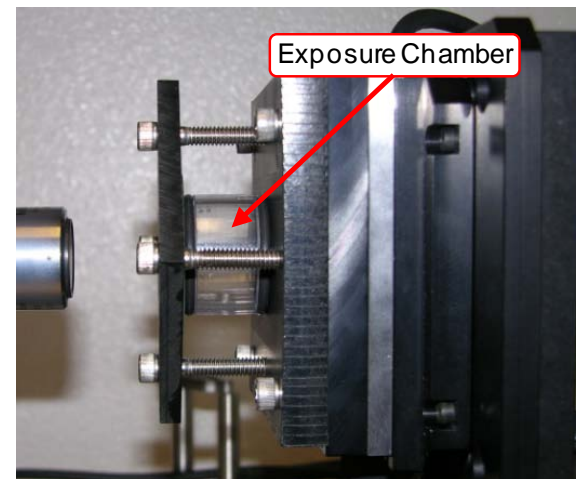
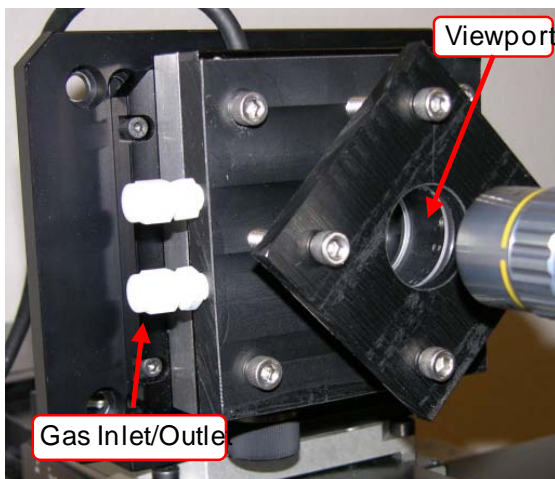
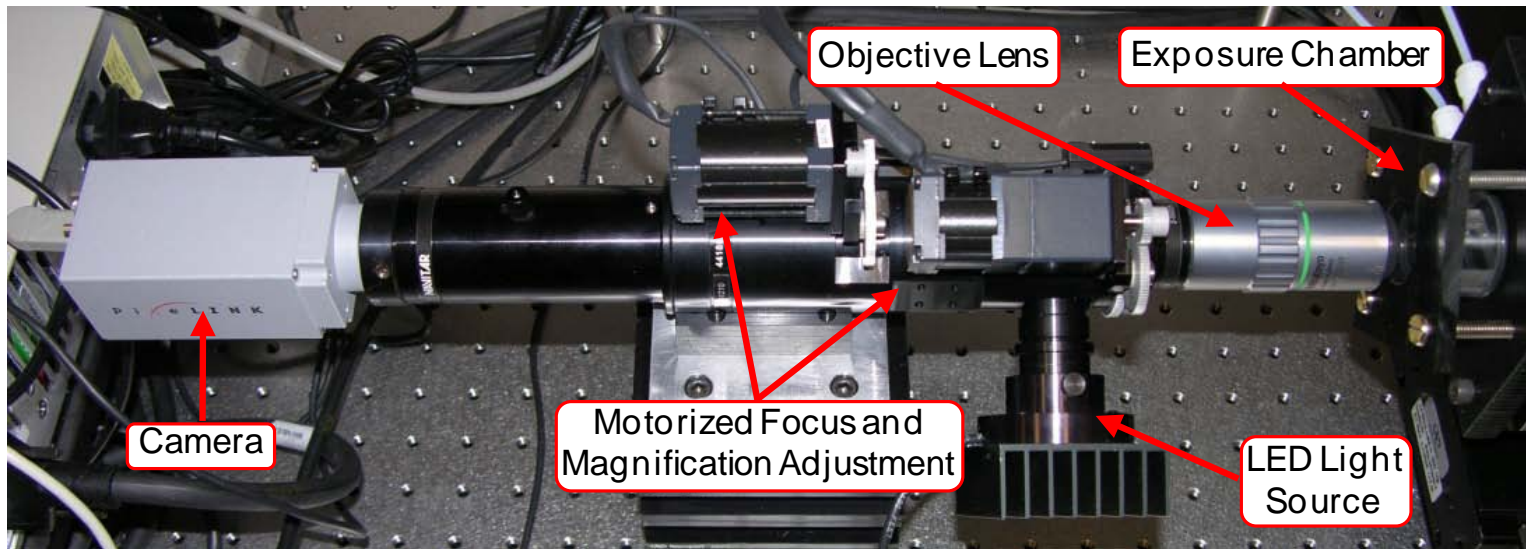
**March 16<sup>th</sup>, 2011**



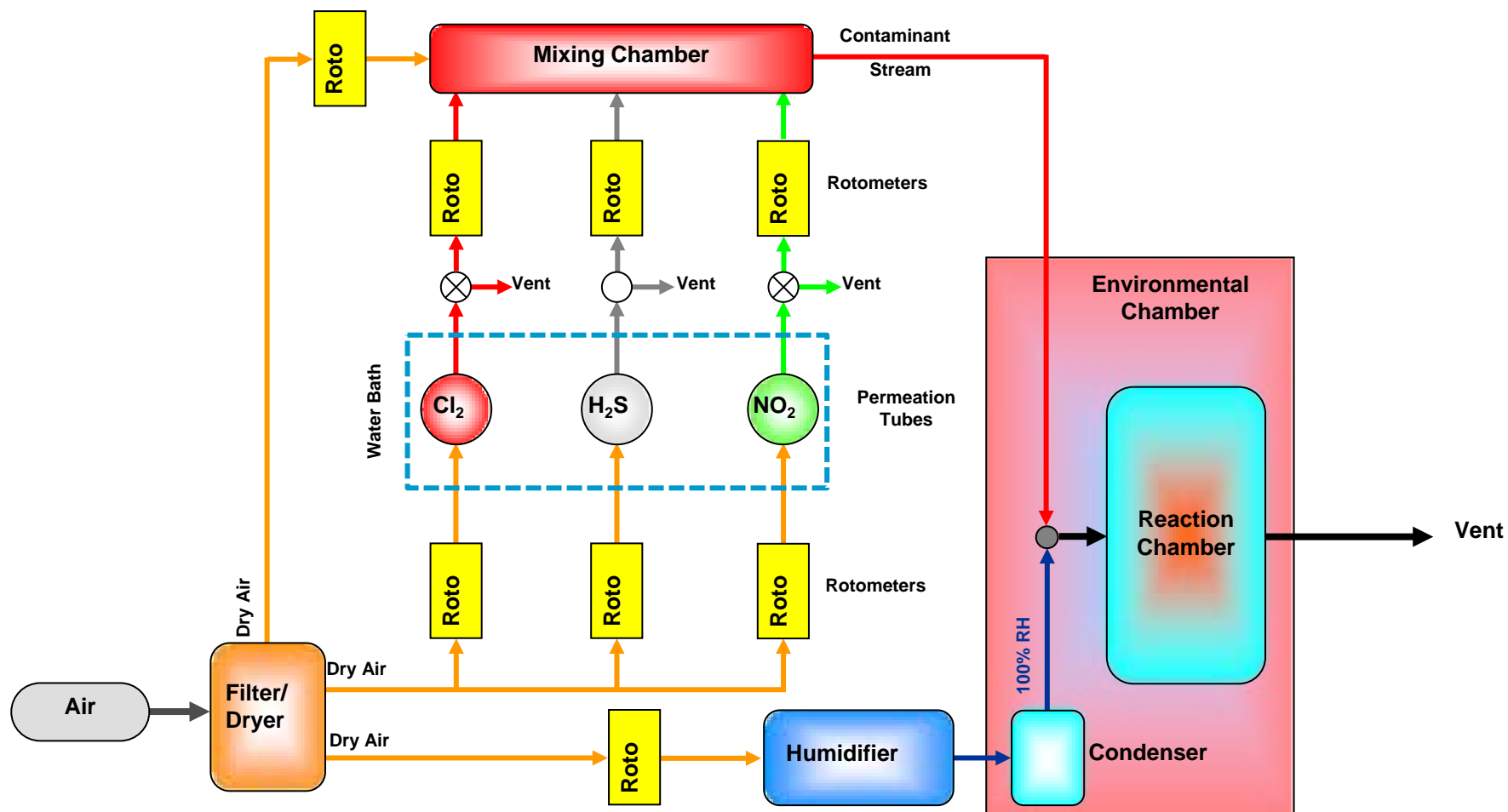
# Background

- **Differential imaging technique for in-situ observation of atmospheric corrosion**
  - Similar to work of Isaacs, et. al (2006) for aqueous samples
  - System consists of imaging hardware/optics along with data acquisition and image analysis software
- **Demonstration of system capabilities performed on noble metal plated copper specimens, simulating metallurgies commonly used in microelectronic connectors**

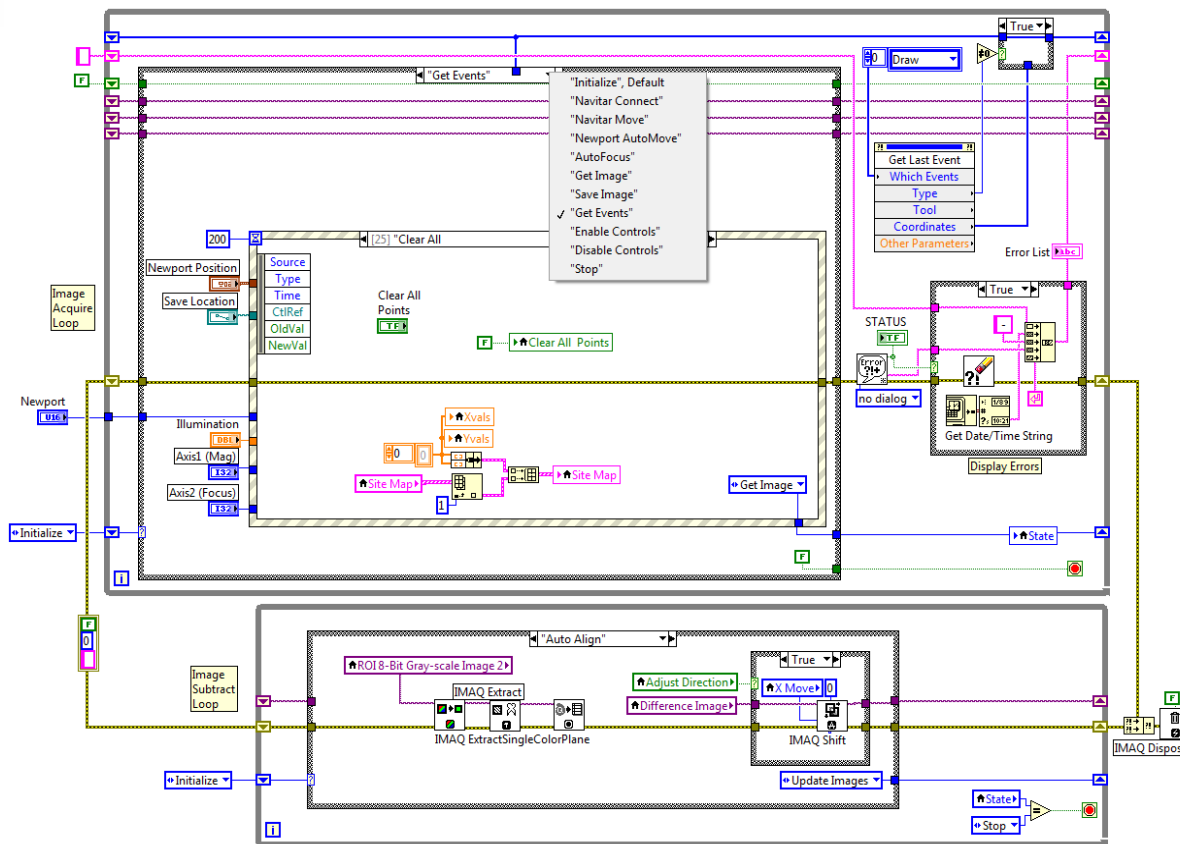
# Differential Imaging System Hardware Configuration



# Environmental Control – Mixed Flowing Gas System

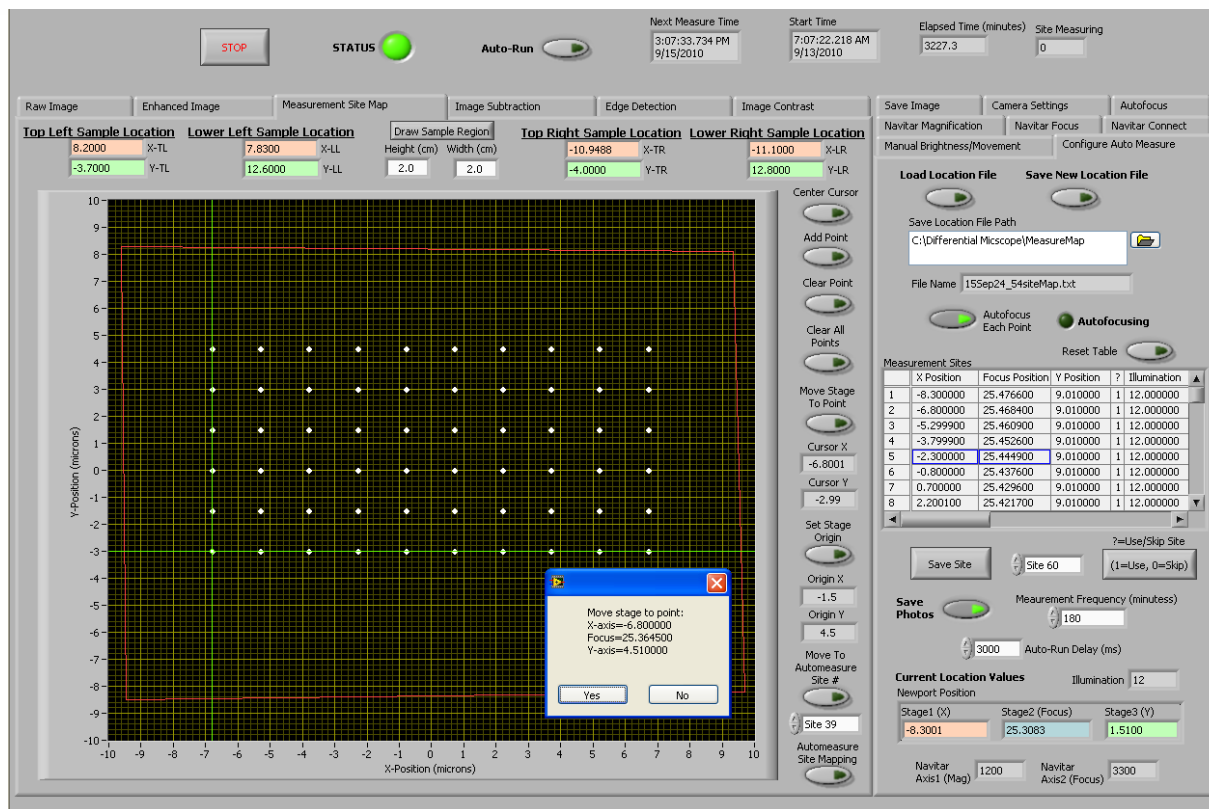


# Data Acquisition and Image Analysis Software



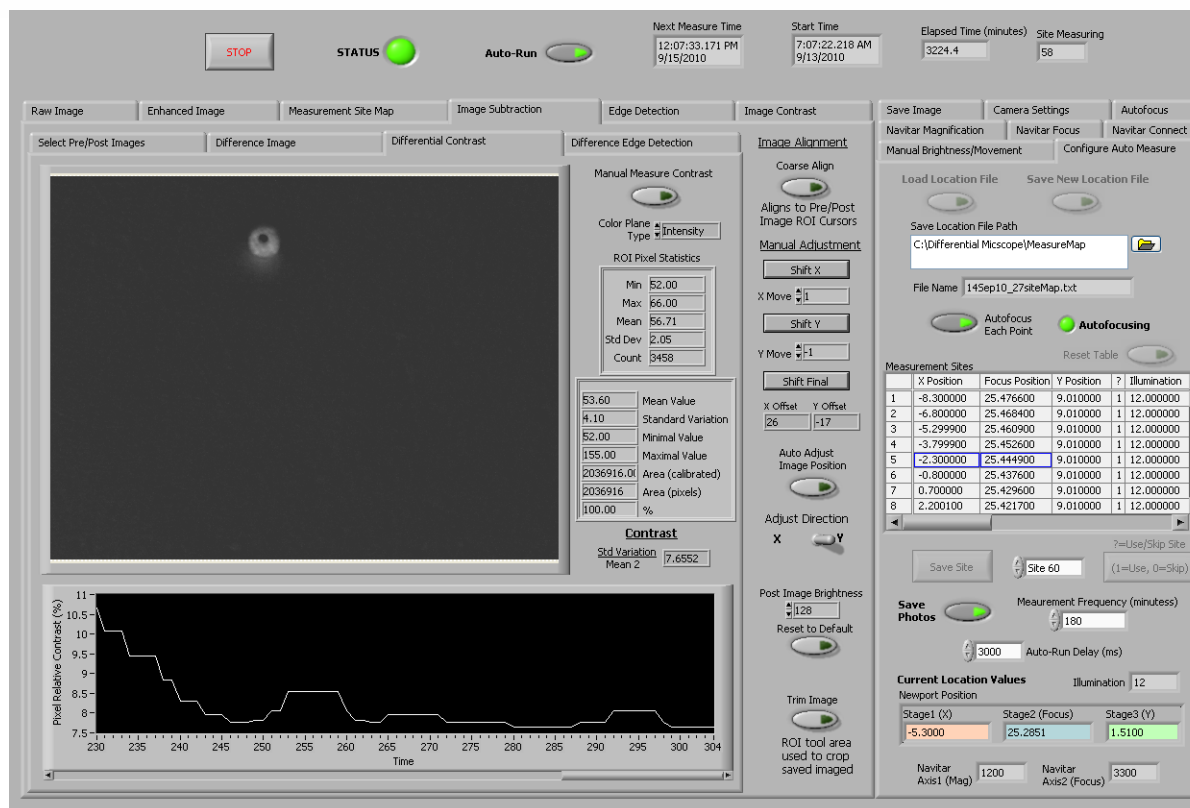
- Code written in NI LabView 2010 and Vision Development Module
- State machine design

# Data Acquisition and Image Analysis Software



- Multiple sites
- Mapping capability with minimal stage backlash/rotation
- Autofocus using Fast Fourier Transform technique

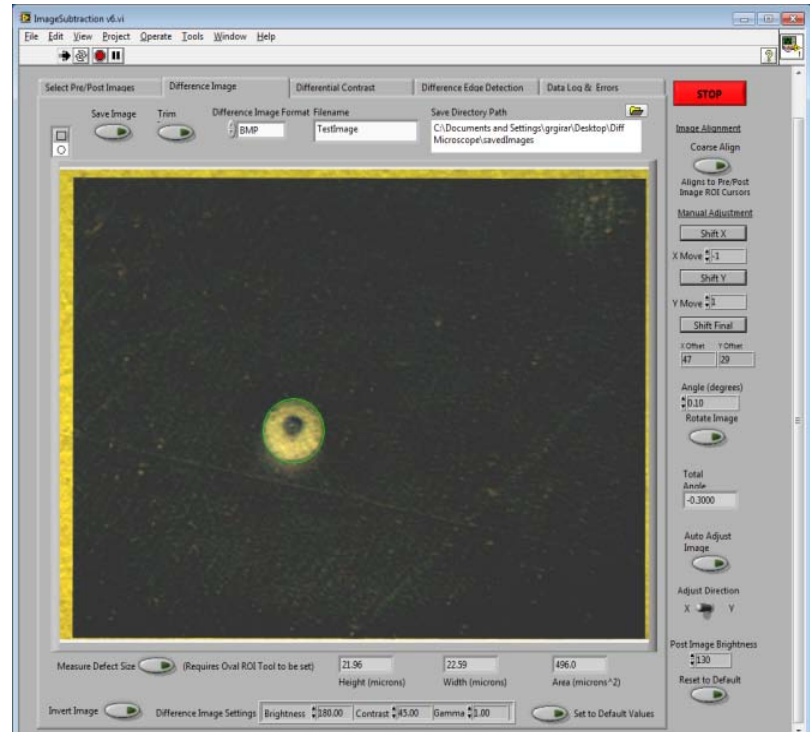
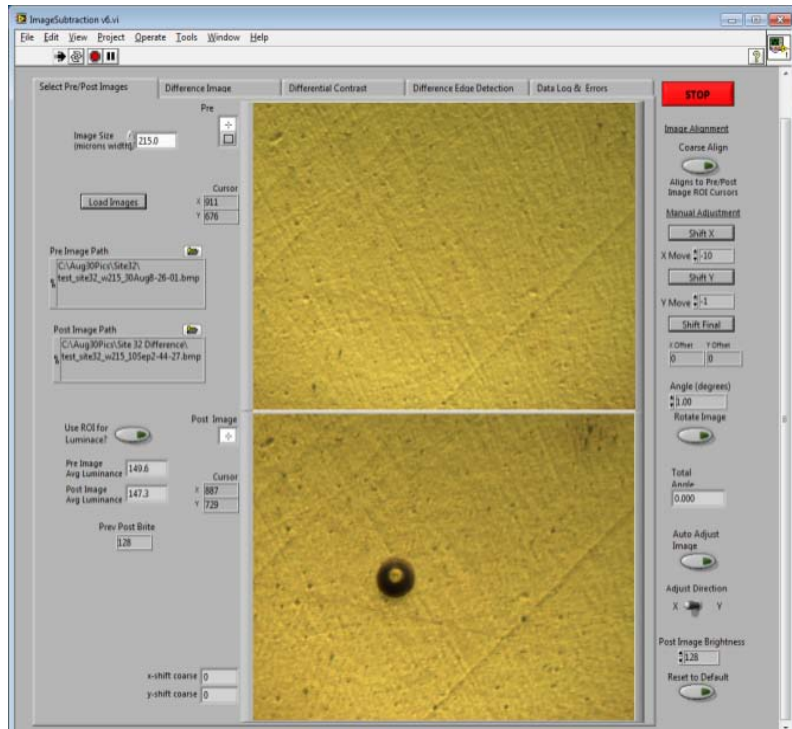
# Data Acquisition and Image Analysis Software



- Integrated and standalone differential image analysis modules
  - Semi-automated image alignment
  - Differential contrast used to verify/establish optimum alignment



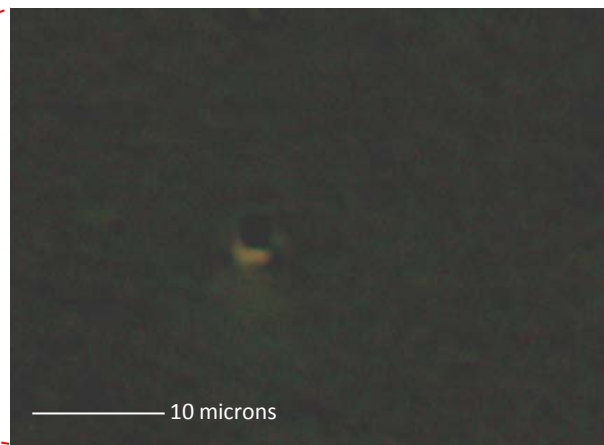
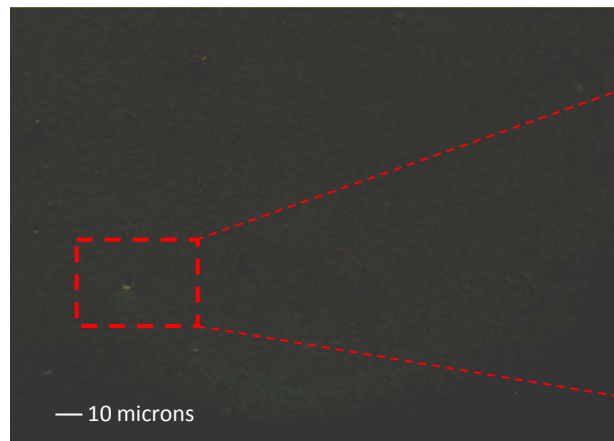
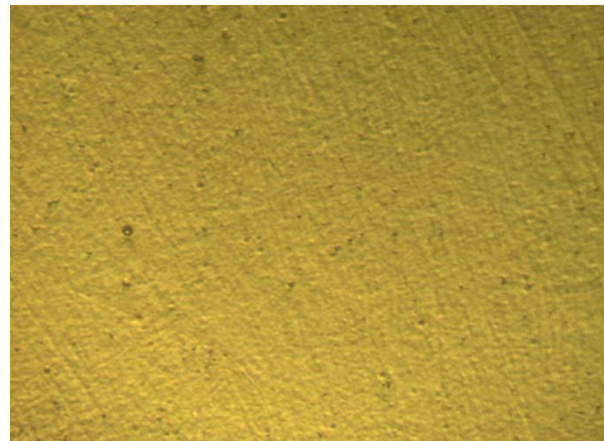
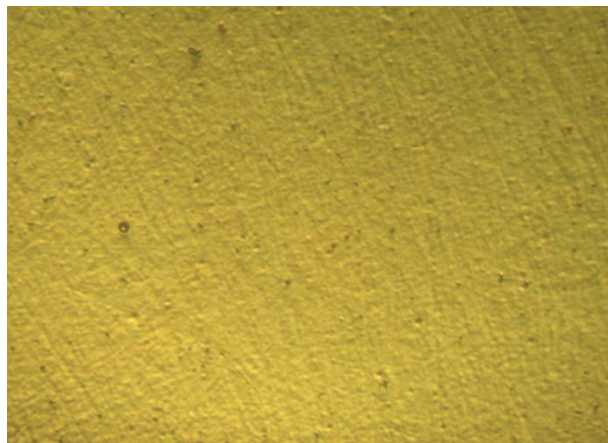
# Data Acquisition and Image Analysis Software



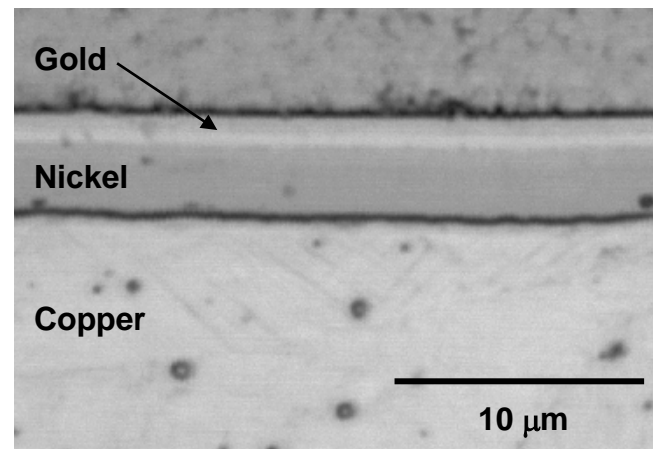
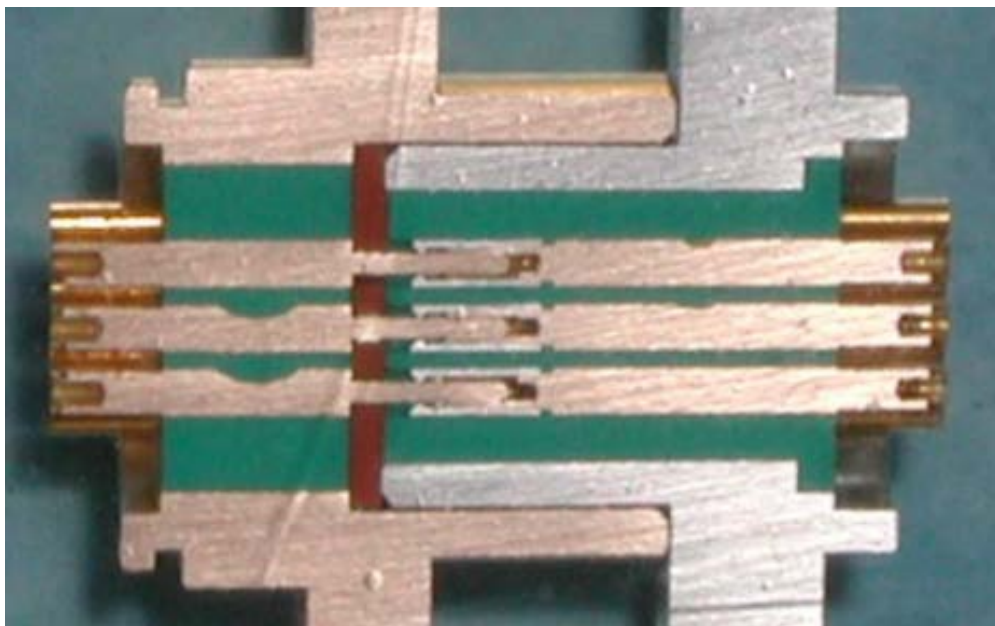
- Pre and post (or live) images combined to form difference image
- Measurement utility to quantify defect size



# Data Acquisition and Image Analysis Software Resolving Individual Defects



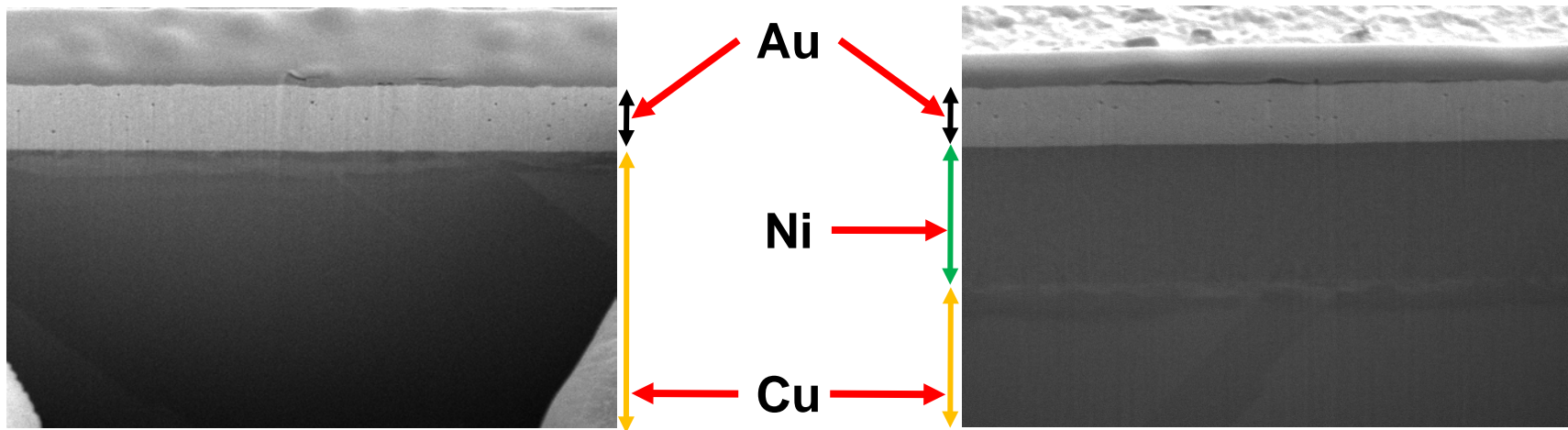
# System Demonstration: Atmospheric Corrosion of Connector Materials



- Atmospheric corrosion of gold plated copper features used in electrical and electronic devices can impact their reliability and effective service life.
- Effective modeling requires that the relevant corrosion degradation phenomena be understood and the key kinetic parameters determined

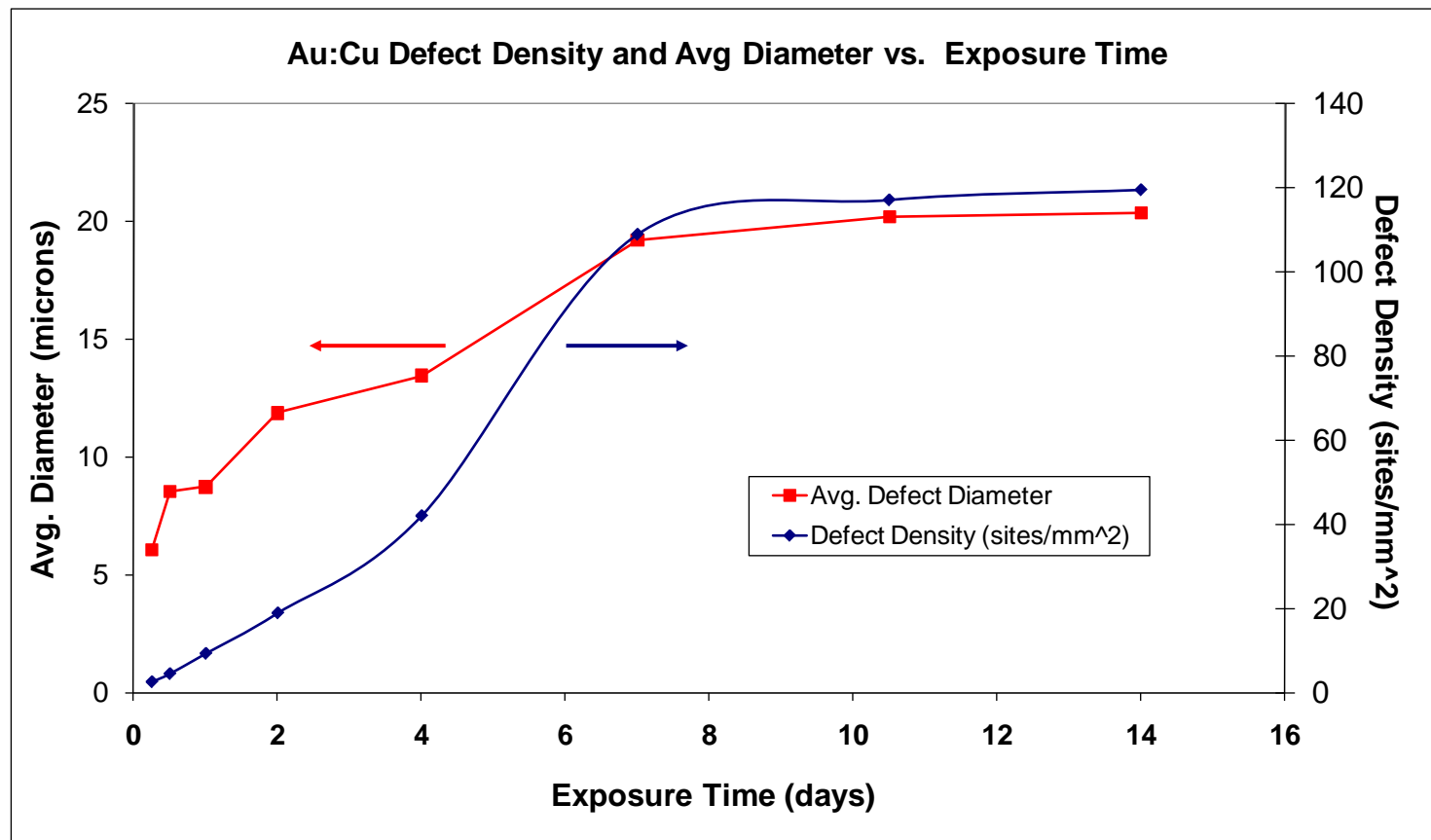
# System Demonstration: Atmospheric Corrosion of Connector Materials

- Oxygen free copper panels, mechanically lapped to a 15-20nm RMS finish
- Electroplated with one of two metallurgies
  - 2.5  $\mu\text{m}$  Au (ASTM Type I, Code C, class 2.5)
  - 2.5  $\mu\text{m}$  Au over 5  $\mu\text{m}$  Ni



# Image Analysis – Defect Density vs. Time

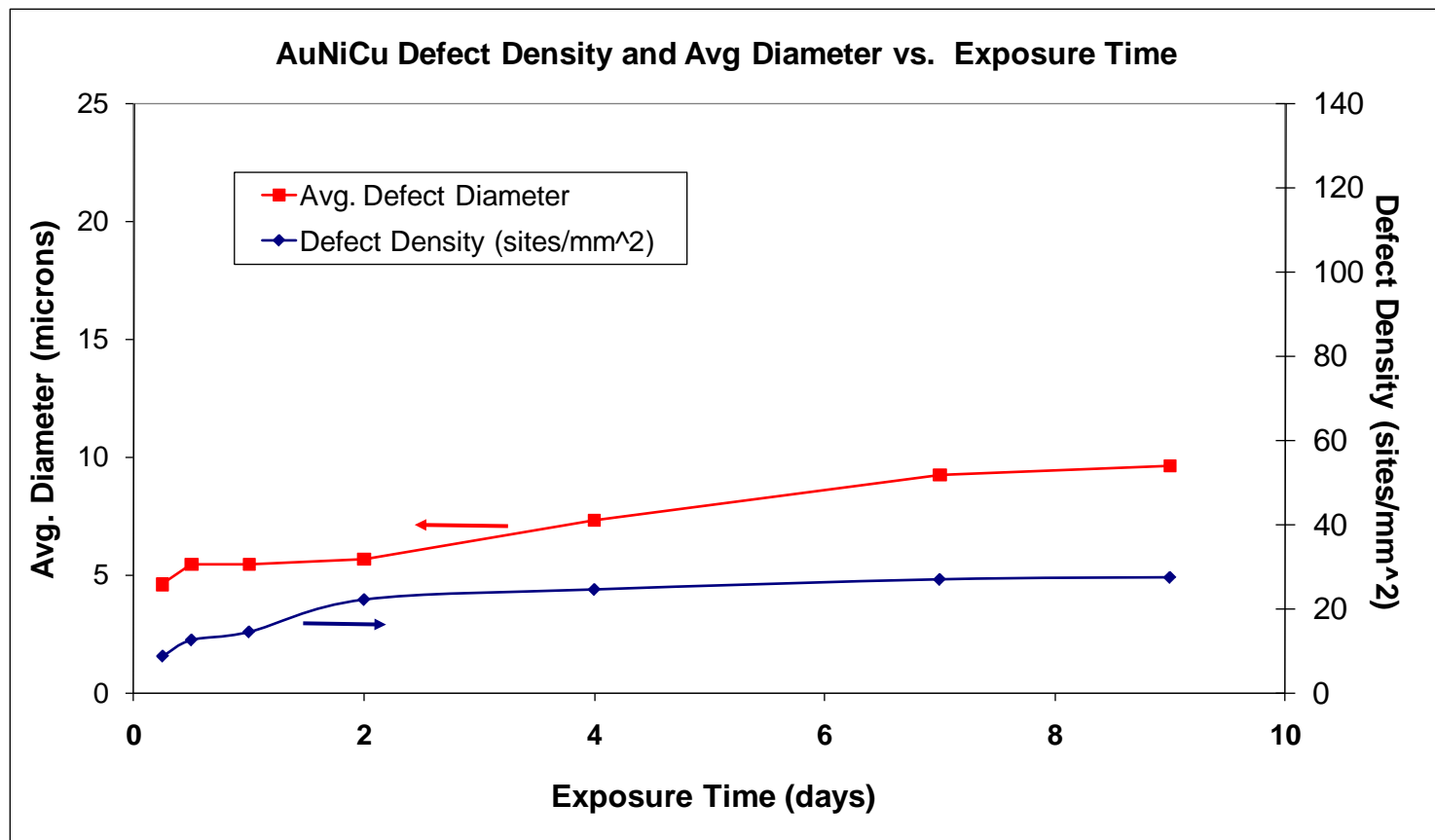
## Au:Cu Samples



- 60 discrete regions monitored as a function of time
- Defect size approximated as a circle

# Image Analysis – Defect Density vs. Time

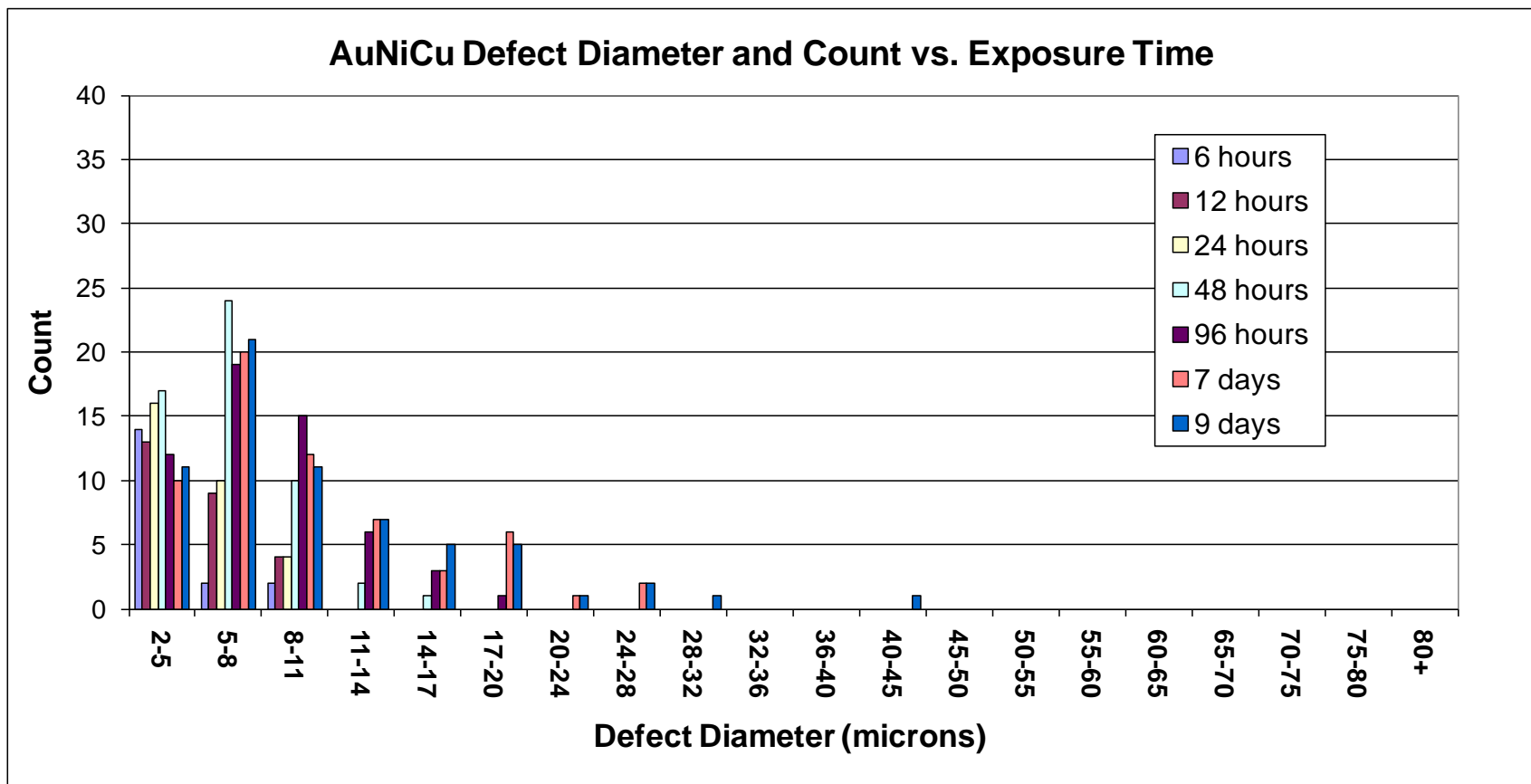
## Au:Ni:Cu Samples



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# Image Analysis – Defect Size Distribution vs. Time

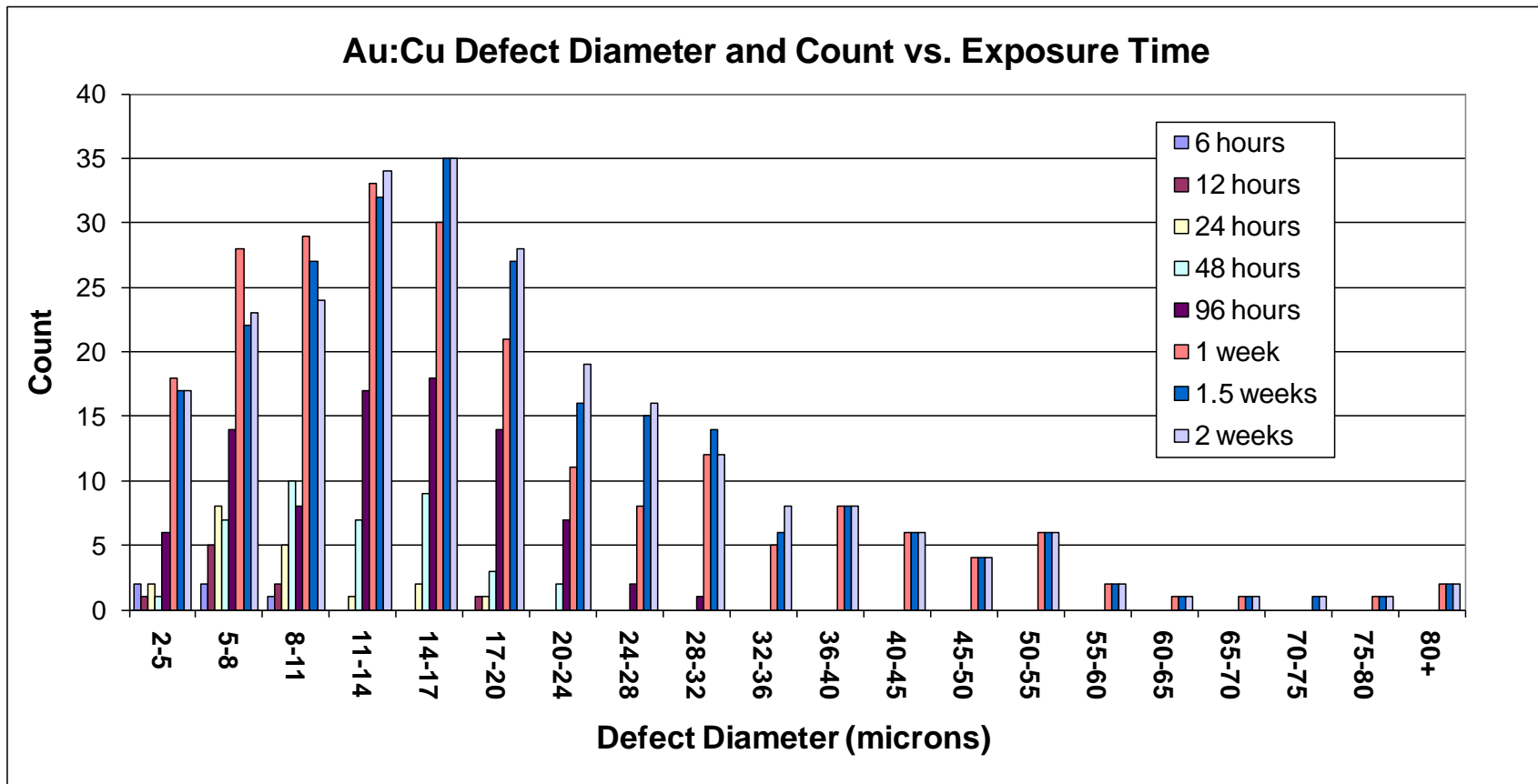
## Au:Cu Samples





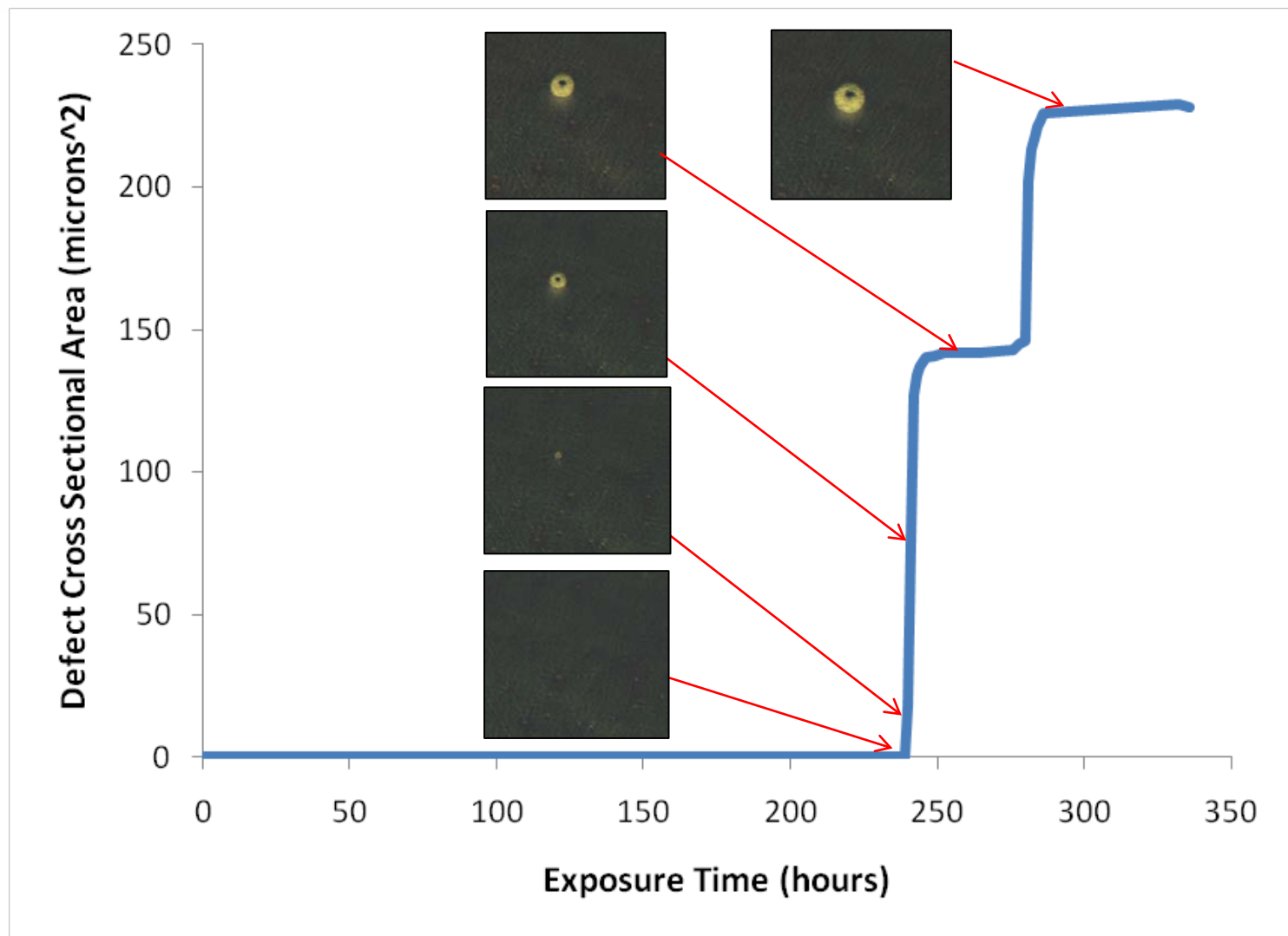
# Image Analysis – Defect Size Distribution vs. Time

## Au:Ni:Cu Samples



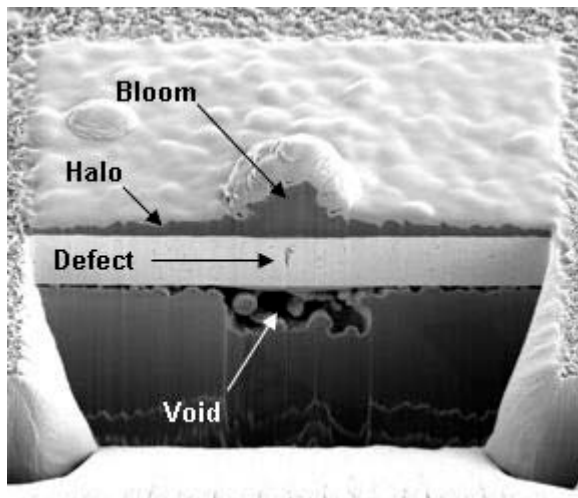
# Image Analysis – Individual Defect Size vs. Time

## Au:Ni:Cu Sample

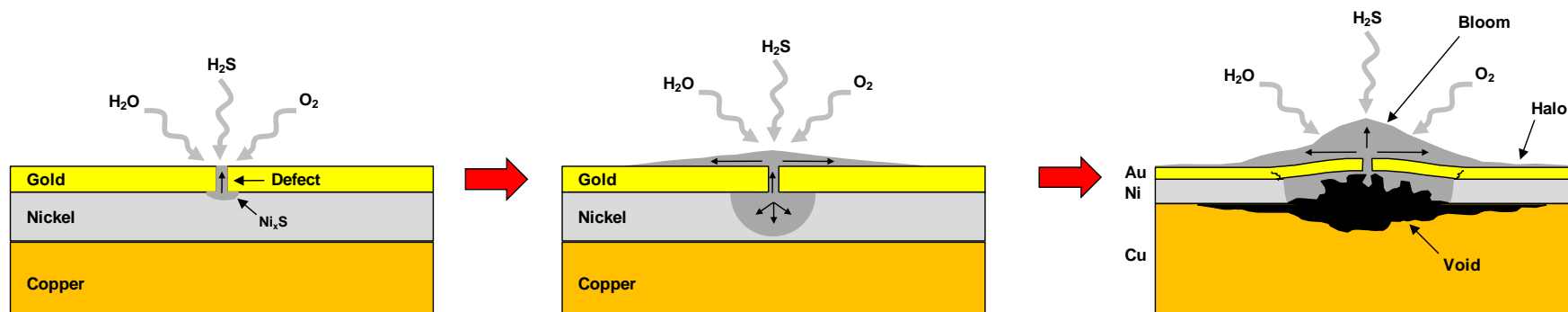
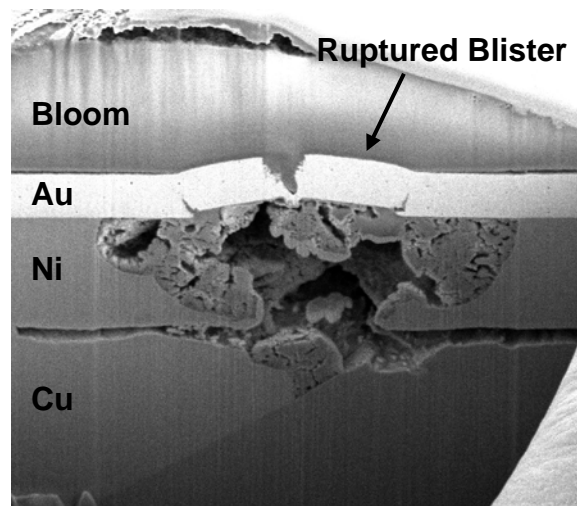


# Why Is There A Multi-Stage Growth Process?

Au:Cu



Au:Ni:Cu





# Summary/Conclusions

- **Differential imaging system has been developed which enables samples undergoing atmospheric corrosion to be imaged in real time**
  - System functionality demonstrated on noble metal plated copper as used in microelectronic connectors
- **System has provided considerable insight into the sulfidation process for noble metal plated copper**
  - Unbiased measure of corrosion site density and size distribution
  - Time dependent evaluation of corrosion site size
    - Multi-stage growth process revealed
    - While additional work is necessary to confirm, experiments to date agree with mechanism proposed for site nucleation, growth, and passivation/stifling